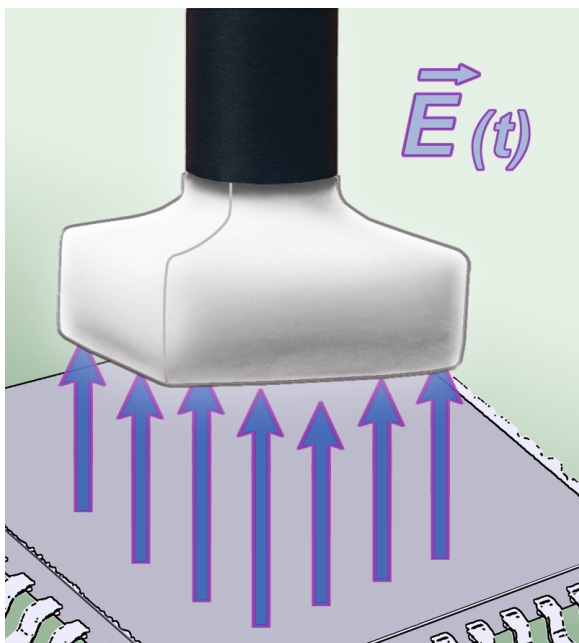


RF-E 09

E-Field Probe 30 MHz up to 3 GHz

LANGER
EMV-Technik



Short description

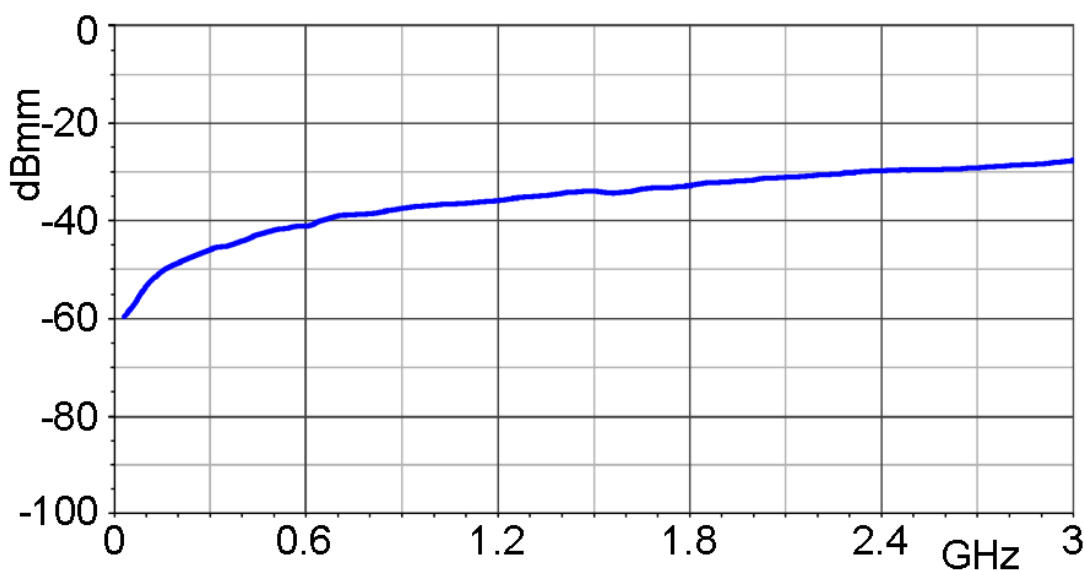
The electrode on the underside of RF-E 09 probe head detects electrical fields decoupled by ICs. The resolution of the probe enables measurements from distances of 0,5 to 10 mm above assemblies. The RF-E 09 probe was developed for Langer scanner.

The RF-E 09 is a passive near-field probe. In principle it has the same structure as the RF-E 03 and RF-E 04 probes. With its small square electrode surface, the specific source of electrical interference field can be detected. For measurements, the E-field probe is held above or positioned onto components and printed circuit boards. The upper half of the probe is electrically shielded. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The E field probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz ... 3 GHz
Probe head dimensions	$\approx (10 \times 10)$ mm
Connector	SMB, male, jack

Frequency response

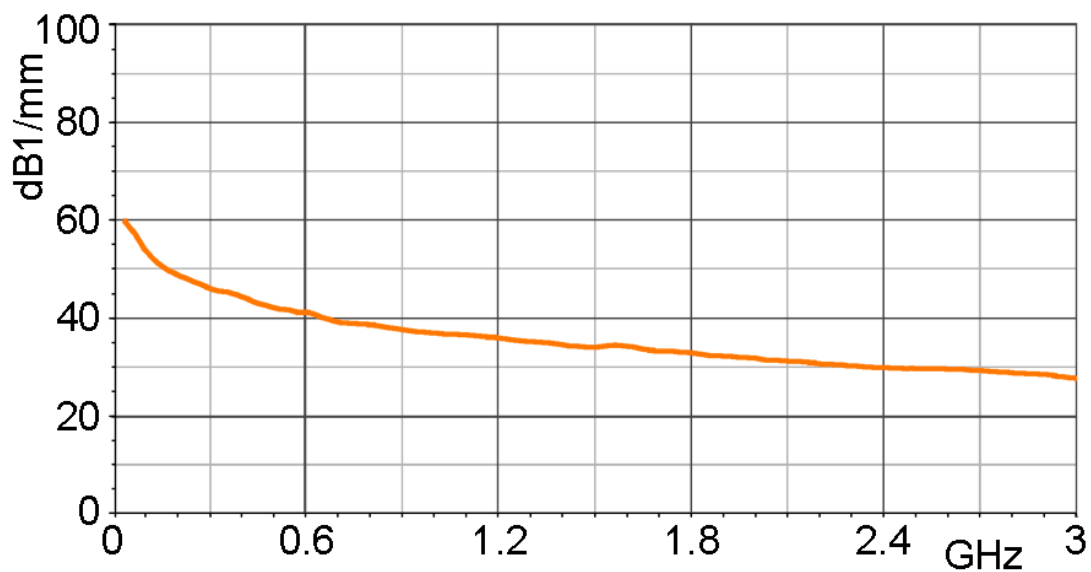


RF-E 09

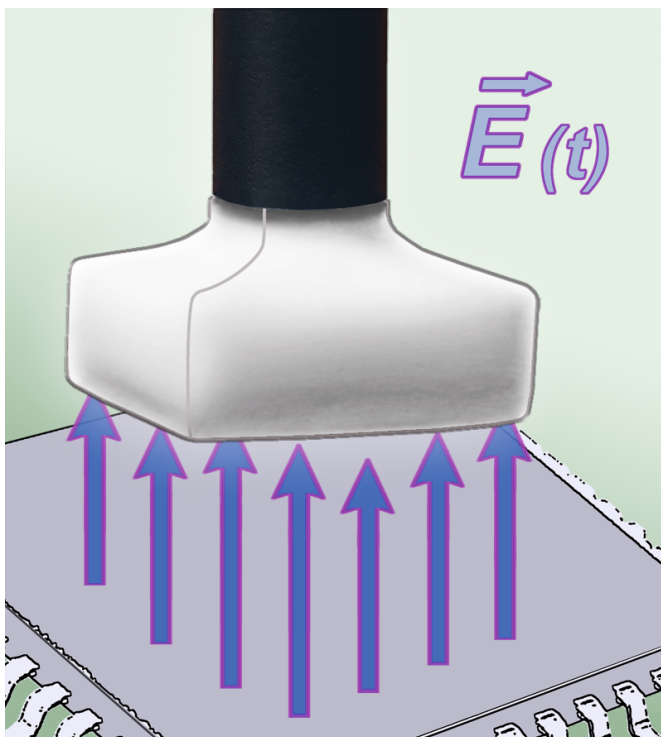
E-Field Probe 30 MHz up to 3 GHz

LANGER
EMV-Technik

E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



RF-E 09

E-Field Probe 30 MHz up to 3 GHz

LANGER
EMV-Technik

Probe head



ES France - Département Tests & Mesures
127 rue de Buzenval BP 26 - 92380 Garches



Tél. 01 47 95 99 45
Fax. 01 47 01 16 22



e-mail : tem@es-france.com
Site Web : www.es-france.com